

Search Notes

Application/Control No.

10/635,419

Examiner

Jacques Veillard

Applicant(s)/Patent under
Reexamination

COBB ET AL.

Art Unit

2165

SEARCHED

Class	Subclass	Date	Examiner
707	3-6,10	6/14/2006	J.V
707	100,101	6/14/2006	J.V
707	102,104.1	6/14/2006	J.V
715	515, 531	6/14/2006	J.V
715	500,513	6/14/2006	J.V
704	1, 2, 4	6/14/2006	J.V
704	8 - 10	6/14/2006	J.V
7704	251, 257	6/19/2006	J.V
709	219	6/19/2006	J.V

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	100	6/20/2006	J.V
707	101	6/20/2006	J.V

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC Plus database search prepared by SIRA staff	4/17/2006	J.V
Search East electronic database	4/24/2006	J.V
Consulted with S. Hong SPE AU 2178 class 715	6/14/2006	J.V
Consulted with R. Dorvil SPE AU 2634 class 704	6/14/2006	J.V
Search West electronic database	6/14/2006	J.V
STIC search and results prepared at EIC TC2100 by SIRA staff	6/20/2006	J.V